

IRF7754

HEXFET® Power MOSFET

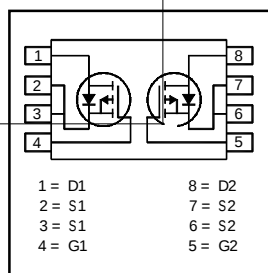
- Ultra Low On-Resistance
- P-Channel MOSFET
- Very Small SOIC Package
- Low Profile (< 1.2mm)
- Available in Tape & Reel

V_{DS}	$R_{DS(on)}$ max	I_D
-12V	25mΩ@ $V_{GS} = -4.5V$	-5.4A
	34mΩ@ $V_{GS} = -2.5V$	-4.6A
	49mΩ@ $V_{GS} = -1.8V$	-3.9A

Description

HEXFET® Power MOSFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the ruggedized device design, that International Rectifier is well known for, provides the designer with an extremely efficient and reliable device for battery and load management.

The TSSOP-8 package has 45% less footprint area than the standard SO-8. This makes the TSSOP-8 an ideal device for applications where printed circuit board space is at a premium. The low profile (<1.2mm) allows it to fit easily into extremely thin environments such as portable electronics and PCMCIA cards.



Absolute Maximum Ratings

	Parameter	Max.	Units
V_{DS}	Drain-Source Voltage	-12	V
I_D @ $T_A = 25^\circ C$	Continuous Drain Current, V_{GS} @ -4.5V	-5.5	A
I_D @ $T_A = 70^\circ C$	Continuous Drain Current, V_{GS} @ -4.5V	-4.4	
I_{DM}	Pulsed Drain Current①	-22	
P_D @ $T_A = 25^\circ C$	Maximum Power Dissipation③	1	W
P_D @ $T_A = 70^\circ C$	Maximum Power Dissipation③	0.64	W
	Linear Derating Factor	0.01	W/°C
V_{GS}	Gate-to-Source Voltage	±8	V
T_J, T_{STG}	Junction and Storage Temperature Range	-55 to +150	°C

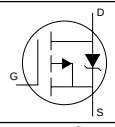
Thermal Resistance

	Parameter	Max.	Units
$R_{\theta JA}$	Maximum Junction-to-Ambient③	125	°C/W

Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	-12	—	—	V	$V_{GS} = 0V$, $I_D = -250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	—	0.008	—	$V/^\circ C$	Reference to $25^\circ C$, $I_D = -1mA$
	—	—	25		$V_{GS} = -4.5V$, $I_D = -5.4A$ ②
	—	—	34		$V_{GS} = -2.5V$, $I_D = -4.6A$ ②
	—	—	49		$V_{GS} = -1.8V$, $I_D = -3.9A$ ②
$V_{GS(th)}$	-0.4	—	-0.9	V	$V_{DS} = V_{GS}$, $I_D = -250\mu A$
g_{fs}	16	—	—	S	$V_{DS} = -10V$, $I_D = -5.4A$
	—	—	-1.0		$V_{DS} = -9.6V$, $V_{GS} = 0V$
	—	—	-25		$V_{DS} = -9.6V$, $V_{GS} = 0V$, $T_J = 70^\circ C$
	—	—	-100		$V_{GS} = -8V$
	—	—	100		$V_{GS} = 8V$
Q_g	—	22	—		$I_D = -5.4A$
Q_{gs}	—	3.9	—	nC	$V_{DS} = -6V$
Q_{gd}	—	4.8	—		$V_{GS} = -4.5V$ ②
$t_{d(on)}$	—	9.8	14.7		$V_{DD} = -6V$, $V_{GS} = -4.5V$
t_r	—	18	27		$I_D = -1.0A$
$t_{d(off)}$	—	267	401		$R_D = 6\Omega$
t_f	—	191	287		$R_G = 6\Omega$ ②
C_{iss}	—	1984	—		$V_{GS} = 0V$
C_{oss}	—	618	—	pF	$V_{DS} = -6V$
C_{rss}	—	385	—		$f = 1.0MHz$

Source-Drain Ratings and Characteristics

Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	—	—	-1.0	A	MOSFET symbol showing the integral reverse p-n junction diode. 
I_{SM}	—	—	-22	A	
V_{SD}	—	—	-1.2	V	$T_J = 25^\circ C$, $I_S = -1.0A$, $V_{GS} = 0V$ ②
t_{rr}	—	39	59	ns	$T_J = 25^\circ C$, $I_F = -1.0A$
Q_{rr}	—	27	41	nC	$di/dt = -100A/\mu s$ ②

Notes:

① Repetitive rating; pulse width limited by max. junction temperature.

② Pulse width $\leq 400\mu s$; duty cycle $\leq 2\%$.

③ When mounted on 1 inch square copper board, $t < 10$ sec.

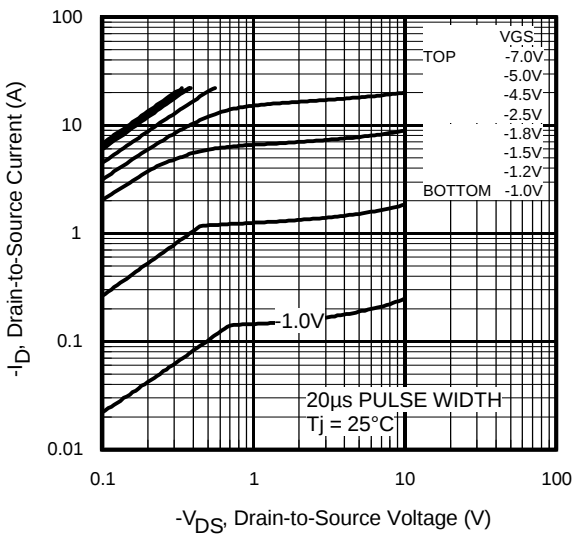


Fig 1. Typical Output Characteristics

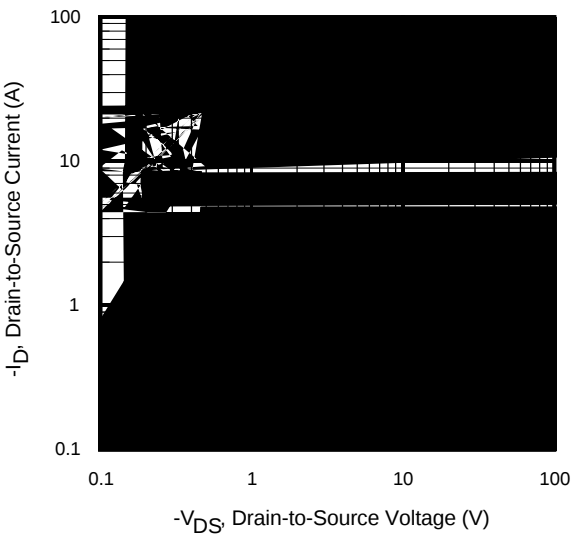


Fig 2. Typical Output Characteristics

Fig 3. Typical Transfer Characteristics

Fig 4. Normalized On-Resistance
Vs. Temperature

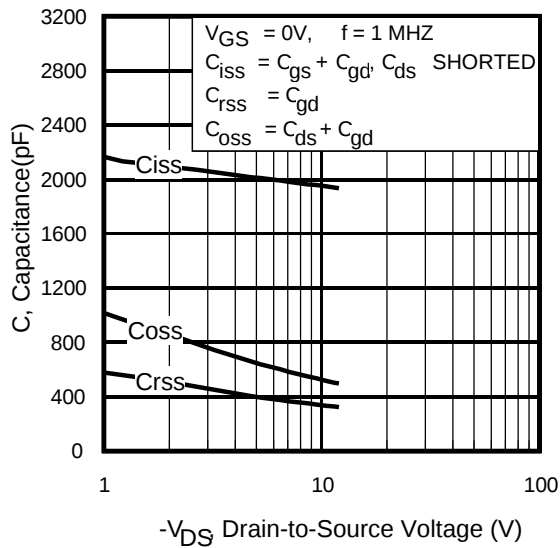


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

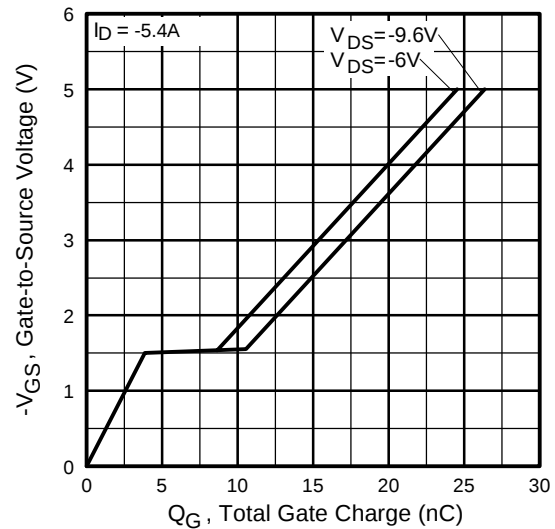


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

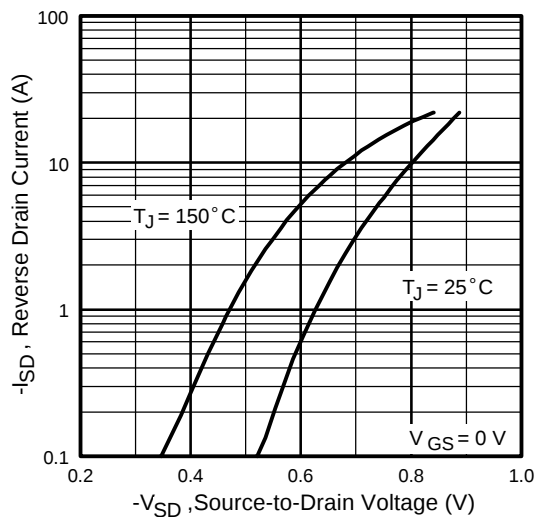


Fig 7. Typical Source-Drain Diode Forward Voltage

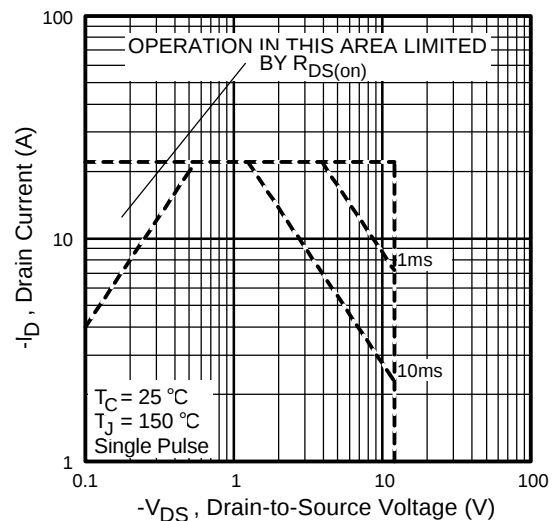


Fig 8. Maximum Safe Operating Area

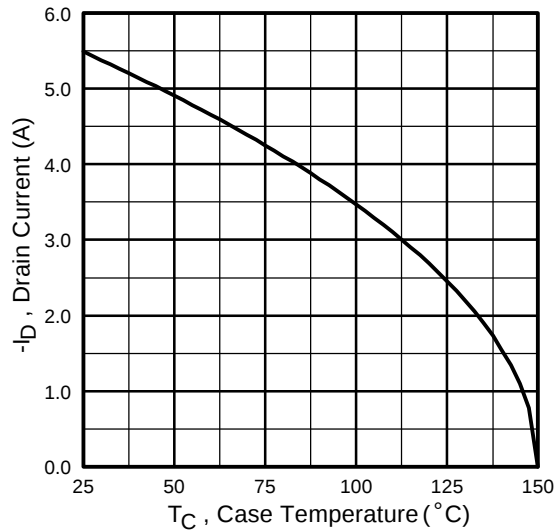


Fig 9. Maximum Drain Current Vs. Case Temperature

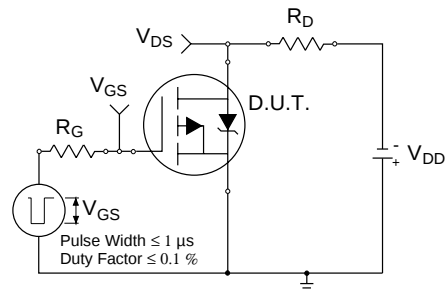


Fig 10a. Switching Time Test Circuit

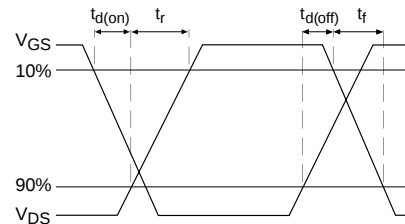


Fig 10b. Switching Time Waveforms

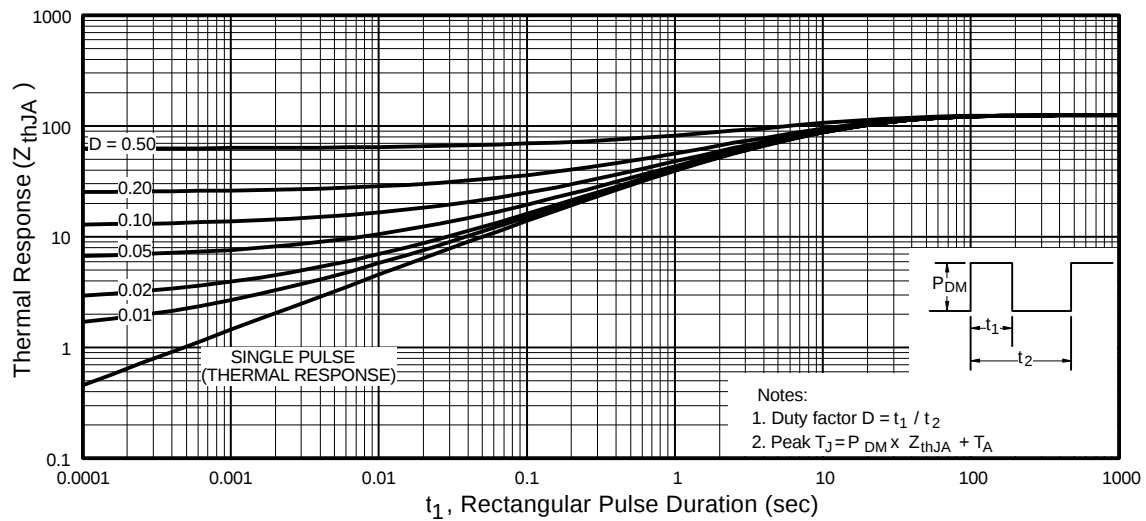


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

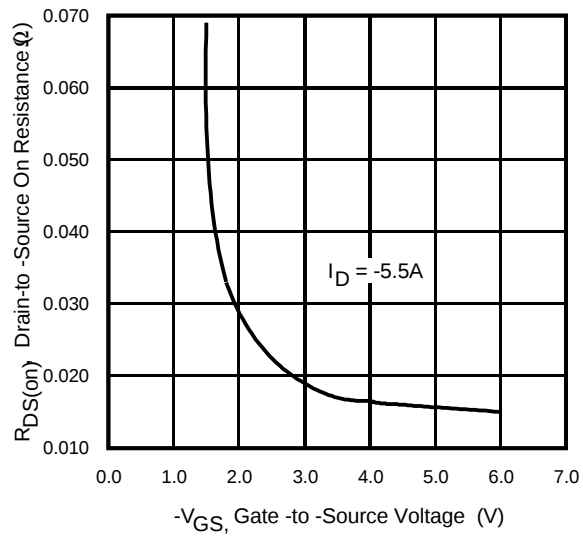


Fig 12. Typical On-Resistance Vs. Gate Voltage

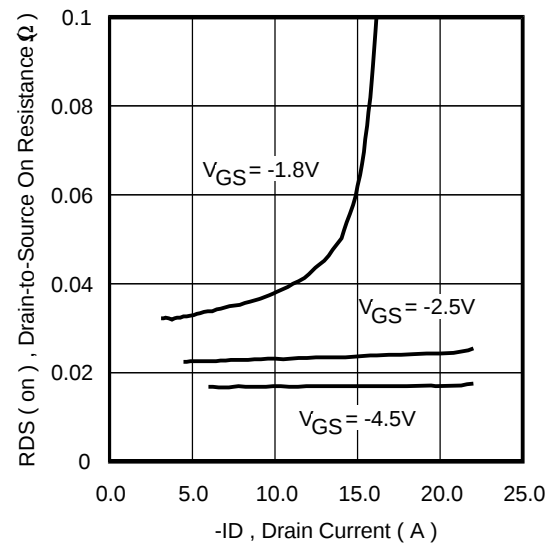


Fig 13. Typical On-Resistance Vs. Drain Current

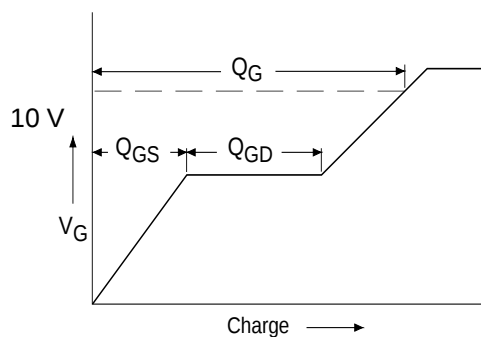


Fig 14a. Basic Gate Charge Waveform

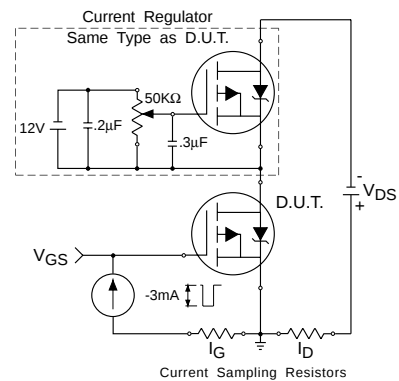


Fig 14b. Gate Charge Test Circuit

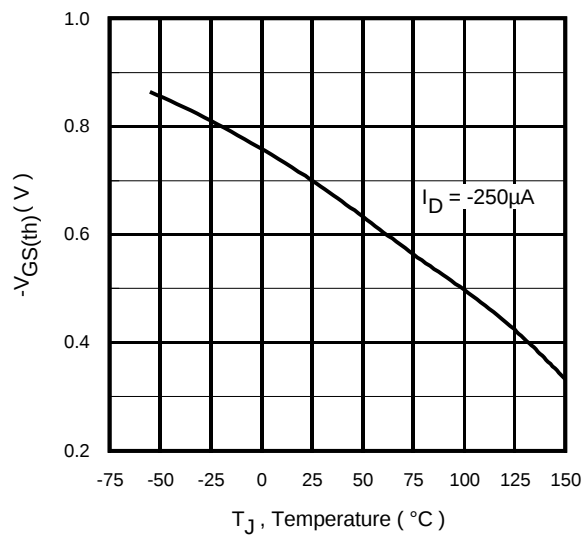


Fig 15. Typical $V_{GS(th)}$ Vs. Junction Temperature

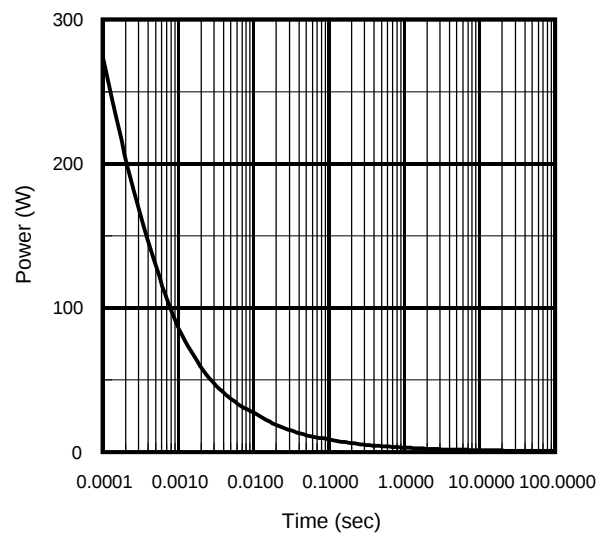


Fig 16. Typical Power Vs. Time

IRF7754

International
IR Rectifier

TSSOP-8 Part Marking Information

EXAMPLE: THIS IS AN IRF7702

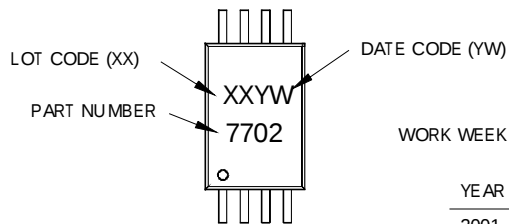


TABLE 1

WORK WEEK 1-26, NUMERIC YEAR CODE (1,2, ...,ETC.)

YEAR	Y	WORK WEEK	W
2001	1	01	A
2002	2	02	B
2003	3	03	C
1994	4	04	D
1995	5		
1996	6		
1997	7		
1998	8		
1999	9		
2000	0	24	X
		25	Y
		26	Z

DATE CODE EXAMPLES:

9503 = 5C
9532 = EF

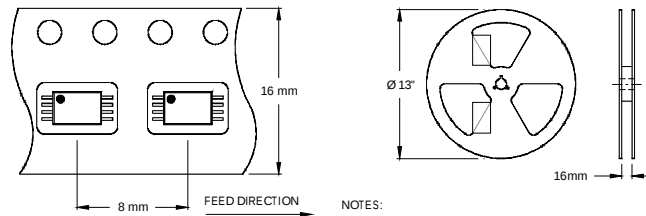
TABLE 2

WORK WEEK 27-52, ALPHANUMERIC YEAR CODE (A,B, ...ETC.)

YEAR	Y	WORK WEEK	W
2001	A	27	A
2002	B	28	B
2003	C	29	C
1994	D	30	D
1995	E		
1996	F		
1997	G		
1998	H		
1999	J		
2000	K	50	X
		51	Y
		52	Z

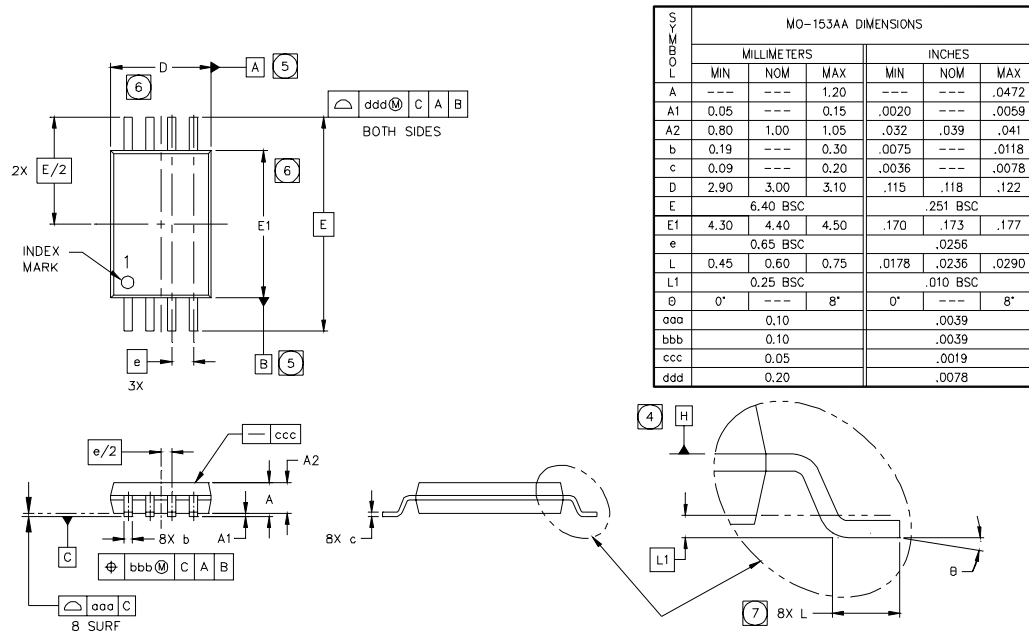
TSSOP-8 Tape and Reel

8LTSSOP (MO-153AA)



NOTES:
1. TAPE & REEL OUTLINE CONFORMS TO EIA-481 & EIA-541.

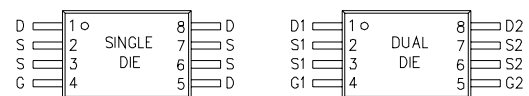
TSSOP-8 Package Outline



NOTES

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.
2. DIMENSIONS ARE SHOWN IN MILLIMETERS AND INCHES.
3. CONTROLLING DIMENSION: MILLIMETER.
4. DATUM PLANE H IS LOCATED AS SHOWN.
5. DATUM A AND B TO BE DETERMINED AT DATUM PLANE H.
6. DIMENSIONS D AND E1 ARE MEASURED AT DATUM PLANE H.
7. DIMENSION L IS THE LEAD LENGTH FOR SOLDERING TO A SUBSTRATE.
8. OUTLINE CONFORMS TO JEDEC OUTLINE MO-153AA.

LEAD ASSIGNMENTS



Data and specifications subject to change without notice.
This product has been designed and qualified for the consumer market.
Qualification Standards can be found on IR's Web site.

International
IR Rectifier

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